| Sea | ircn | Note | S |
|-----|------|------|---|
|     |      |      |   |
|     |      |      |   |
|     |      |      |   |

| Application/Control No. | Applicant(s)/Patent under Reexamination | _ |
|-------------------------|---|---|
| 10/664,637              | HANEY ET AL.                            |   |
| Examiner                | Art Unit                                |   |
| David E. Bochna         | 3679                                    |   |

|       | SEARCHED |      |          |
|-------|----------|------|----------|
| Class | Subclass | Date | Examiner |
|       |          |      |          |
|       |          |      |          |
|       |          | _    |          |
|       |          |      | ·        |
|       |          |      |          |
|       |          |      |          |
|       |          |      |          |
|       |          |      |          |
|       |          |      |          |
|       |          |      |          |
|       |          |      |          |
|       |          |      |          |
|       |          |      |          |
|       |          |      |          |
|       |          |      |          |

| INT   | INTERFERENCE SEARCHED |           |          |  |
|-------|-----------------------|-----------|----------|--|
| Class | Subclass              | Date      | Examiner |  |
| 285   | 390, 333              | 8/22/2006 | DB       |  |
|       | 334, 115              |           |          |  |
|       | 423                   | ,         |          |  |
|       | :                     |           |          |  |
|       |                       |           |          |  |

| DATE      | EXMR |
|-----------|------|
|           |      |
| 8/22/2006 | DB   |
|           |      |
|           |      |
|           |      |
|           |      |
|           |      |
|           |      |
|           |      |
|           |      |
| _         |      |